

Welcome to [E-XFL.COM](#)

Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	12675
Number of Logic Elements/Cells	162240
Total RAM Bits	11980800
Number of I/O	285
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	484-BBGA, FCBGA
Supplier Device Package	484-FCBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7k160t-2fbg484c

Table 1: Absolute Maximum Ratings (1) (Cont'd)

Symbol	Description	Min	Max	Units
I _{DCIN}	DC input current for receiver input pins DC coupled V _{MGTAVTT} = 1.2V	–	14	mA
I _{DCOUT}	DC output current for transmitter pins DC coupled V _{MGTAVTT} = 1.2V	–	14	mA
XADC				
V _{CCADC}	XADC supply relative to GNDADC	–0.5	2.0	V
V _{REFP}	XADC reference input relative to GNDADC	–0.5	2.0	V
Temperature				
T _{STG}	Storage temperature (ambient)	–65	150	°C
T _{SOL}	Maximum soldering temperature for Pb/Sn component bodies (6)	–	+220	°C
	Maximum soldering temperature for Pb-free component bodies (6)	–	+260	°C
T _j	Maximum junction temperature(6)	–	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- The lower absolute voltage specification always applies.
- For I/O operation, refer to [UG471: 7 Series FPGAs SelectIO Resources User Guide](#).
- The maximum limit applied to DC and AC signals.
- For maximum undershoot and overshoot AC specifications, see [Table 4](#) and [Table 5](#).
- For soldering guidelines and thermal considerations, see [UG475: 7 Series FPGA Packaging and Pinout Specification](#).

Table 2: Recommended Operating Conditions (1)

Symbol	Description	Min	Typ	Max	Units
FPGA Logic					
V _{CCINT} ⁽²⁾	Internal supply voltage	0.97	1.00	1.03	V
	For -2L (0.9V) devices: internal supply voltage	0.87	0.90	0.93	V
V _{CCBRAM} ⁽²⁾	Block RAM supply voltage	0.97	1.00	1.03	V
	For -2L (0.9V) devices: block RAM supply voltage	0.87	0.90	1.03	V
V _{CCAUX}	Auxiliary supply voltage	1.71	1.80	1.89	V
V _{CCO} ⁽³⁾⁽⁴⁾	Supply voltage for 3.3V HR I/O banks	1.14	–	3.465	V
	Supply voltage for 1.8V HP I/O banks	1.14	–	1.89	V
V _{CCAUX_IO}	Auxiliary supply voltage when set to 1.8V	1.71	1.80	1.89	V
	Auxiliary supply voltage when set to 2.0V	1.94	2.00	2.06	V
V _{IN} ⁽⁵⁾	I/O input voltage	–0.20	–	V _{CCO} + 0.2	V
	I/O input voltage for V _{REF} and differential I/O standards	–0.20	–	2.625	V
I _{IN} ⁽⁶⁾	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	–	10	mA
V _{CCBATT} ⁽⁷⁾	Battery voltage	1.0	–	1.89	V
GTX Transceiver					
V _{MGTAVCC} ⁽⁸⁾	Analog supply voltage for the GTX transceiver QPLL frequency range ≤ 10.3125 GHz ⁽⁹⁾⁽¹⁰⁾	0.97	1.0	1.08	V
	Analog supply voltage for the GTX transceiver QPLL frequency range > 10.3125 GHz	1.02	1.05	1.08	V
V _{MGTAVTT} ⁽⁸⁾	Analog supply voltage for the GTX transmitter and receiver termination circuits	1.17	1.2	1.23	V
V _{MGTVCaux} ⁽⁸⁾	Auxiliary analog QPLL voltage supply for the transceivers	1.75	1.80	1.85	V

Table 2: Recommended Operating Conditions (1) (Cont'd)

Symbol	Description	Min	Typ	Max	Units
$V_{MGTAVTTRCAL}$ (8)	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	1.17	1.2	1.23	V
XADC					
V_{CCADC}	XADC supply relative to GNDADC	1.71	1.80	1.89	V
V_{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
Temperature					
T_j	Junction temperature operating range for commercial (C) temperature devices	0	–	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	–	100	°C
	Junction temperature operating range for industrial (I) temperature devices	–40	–	100	°C

Notes:

1. All voltages are relative to ground.
2. V_{CCINT} and V_{CCBRAM} should be connected to the same supply.
3. Configuration data is retained even if V_{CCO} drops to 0V.
4. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
5. The lower absolute voltage specification always applies.
6. A total of 200 mA per bank should not be exceeded.
7. V_{CCBATT} is required only when using bitstream encryption. If battery is not used, connect V_{CCBATT} to either ground or V_{CCAUX} .
8. Each voltage listed requires the filter circuit described in [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#).
9. For data rates ≤ 10.3125 Gb/s, $V_{MGTAVCC}$ should be $1.0V \pm 3\%$ for lower power consumption.
10. For lower power consumption, $V_{MGTAVCC}$ should be $1.0V \pm 3\%$ over the entire CPLL frequency range.

Table 3: DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Min	Typ	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	–	–	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	1.5	–	–	V
I_{REF}	V_{REF} leakage current per pin	–	–	15	μA
I_L	Input or output leakage current per pin (sample-tested)	–	–	15	μA
C_{IN} (2)	Die input capacitance at the pad	–	–	8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 3.3V$	90	–	330	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 2.5V$	68	–	250	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.8V$	34	–	220	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.5V$	23	–	150	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.2V$	12	–	120	μA
I_{RPD}	Pad pull-down (when selected) @ $V_{IN} = 3.3V$	68	–	330	μA
	Pad pull-down (when selected) @ $V_{IN} = 1.8V$	45	–	180	μA
I_{CCADC}	Analog supply current, analog circuits in powered up state	–	–	25	mA
I_{BATT} (3)	Battery supply current	–	–	150	nA

Table 3: DC Characteristics Over Recommended Operating Conditions (Cont'd)

Symbol	Description	Min	Typ ⁽¹⁾	Max	Units
$R_{IN_TERM}^{(4)}$	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_40) for commercial (C), industrial (I), and extended (E) temperature devices	28	40	55	Ω
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_50) for commercial (C), industrial (I), and extended (E) temperature devices	35	50	65	Ω
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_60) for commercial (C), industrial (I), and extended (E) temperature devices	44	60	83	Ω
n	Temperature diode ideality factor	—	1.010	—	—
r	Temperature diode series resistance	—	2	—	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. This measurement represents the die capacitance at the pad, not including the package.
3. Maximum value specified for worst case process at 25°C.
4. Termination resistance to a $V_{CCO}/2$ level.

Table 4: Maximum Allowed AC Voltage Overshoot and Undershoot for 3.3V HR I/O Banks⁽¹⁾

AC Voltage Overshoot	% of UI @-40°C to 100°C	AC Voltage Undershoot	% of UI @-40°C to 100°C
$V_{CCO} + 0.40$	100	-0.40	100
$V_{CCO} + 0.45$	100	-0.45	61.7
$V_{CCO} + 0.50$	100	-0.50	25.8
$V_{CCO} + 0.55$	100	-0.55	11.0
$V_{CCO} + 0.60$	46.6	-0.60	4.77
$V_{CCO} + 0.65$	21.2	-0.65	2.10
$V_{CCO} + 0.70$	9.75	-0.70	0.94
$V_{CCO} + 0.75$	4.55	-0.75	0.43
$V_{CCO} + 0.80$	2.15	-0.80	0.20
$V_{CCO} + 0.85$	1.02	-0.85	0.09
$V_{CCO} + 0.90$	0.49	-0.90	0.04
$V_{CCO} + 0.95$	0.24	-0.95	0.02

Notes:

1. A total of 200 mA per bank should not be exceeded.

Table 5: Maximum Allowed AC Voltage Overshoot and Undershoot for 1.8V HP I/O Banks⁽¹⁾⁽²⁾

AC Voltage Overshoot	% of UI @-40°C to 100°C	AC Voltage Undershoot	% of UI @-40°C to 100°C
$V_{CCO} + 0.40$	100	-0.40	100
$V_{CCO} + 0.45$	100	-0.45	100
$V_{CCO} + 0.50$	100	-0.50	100
$V_{CCO} + 0.55$	100	-0.55	100
$V_{CCO} + 0.60$	50.0	-0.60	50.0
$V_{CCO} + 0.65$	50.0	-0.65	50.0
$V_{CCO} + 0.70$	47.0	-0.70	50.0
$V_{CCO} + 0.75$	21.2	-0.75	50.0

Table 6: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
I _{CCBRAMQ}	Quiescent V _{CCBRAM} supply current	XC7K70T	6	6	6	6	mA
		XC7K160T	14	14	14	14	mA
		XC7K325T	19	19	19	19	mA
		XC7K355T	31	31	31	31	mA
		XC7K410T	34	34	34	34	mA
		XC7K420T	41	41	41	41	mA
		XC7K480T	41	41	41	41	mA

Notes:

1. Typical values are specified at nominal voltage, 85°C junction temperatures (T_j) with single-ended SelectIO resources.
2. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
3. Use the XPower™ Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified.

Power-On/Off Power Supply Sequencing

The recommended power-on sequence is V_{CCINT} , V_{CCBRAM} , V_{CCAUX} , V_{CCAUX_IO} , and V_{CCO} to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If V_{CCINT} and V_{CCBRAM} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously. If V_{CCAUX} , V_{CCAUX_IO} , and V_{CCO} have the same recommended voltage levels then they can be powered by the same supply and ramped simultaneously.

For V_{CCO} voltages of 3.3V in HR I/O banks and configuration bank 0:

- The voltage difference between V_{CCO} and V_{CCAUX} must not exceed 2.625V for longer than $T_{VCCO2VCCAUX}$ for each power-on/off cycle to maintain device reliability levels.
- The $T_{VCCO2VCCAUX}$ time can be allocated in any percentage between the power-on and power-off ramps.

The recommended power-on sequence to achieve minimum current draw for the GTX transceivers is V_{CCINT} , $V_{MGTAVCC}$, $V_{MGTAVTT}$ OR $V_{MGTAVCC}$, V_{CCINT} , $V_{MGTAVTT}$. There is no recommended sequencing for $V_{MGTAVCCAUX}$. Both $V_{MGTAVCC}$ and V_{CCINT} can be ramped simultaneously. The recommended power-off sequence is the reverse of the power-on sequence to achieve minimum current draw.

If these recommended sequences are not met, current drawn from $V_{MGTAVTT}$ can be higher than specifications during power-up and power-down.

- When $V_{MGTAVTT}$ is powered before $V_{MGTAVCC}$ and $V_{MGTAVTT} - V_{MGTAVCC} > 150$ mV and $V_{MGTAVCC} < 0.7V$, the $V_{MGTAVTT}$ current draw can increase by 460 mA per transceiver during $V_{MGTAVCC}$ ramp up. The duration of the current draw can be up to $0.3 \times T_{MGTAVCC}$ (ramp time from GND to 90% of $V_{MGTAVCC}$). The reverse is true for power-down.
- When $V_{MGTAVTT}$ is powered before V_{CCINT} and $V_{MGTAVTT} - V_{CCINT} > 150$ mV and $V_{CCINT} < 0.7V$, the $V_{MGTAVTT}$ current draw can increase by 50 mA per transceiver during V_{CCINT} ramp up. The duration of the current draw can be up to $0.3 \times T_{VCCINT}$ (ramp time from GND to 90% of V_{CCINT}). The reverse is true for power-down.

Table 7 shows the minimum current, in addition to I_{CCQ} , that are required by Kintex-7 devices for proper power-on and configuration. If the current minimums shown in **Table 6** and **Table 7** are met, the device powers on after all five supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after V_{CCINT} is applied.

Once initialized and configured, use the XPower tools to estimate current drain on these supplies.

Table 7: Power-On Current for Kintex-7 Devices

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	I_{CCAUX_IOMIN}	$I_{CCBRAMMIN}$	Units
	Typ ⁽¹⁾	Typ ⁽¹⁾	Typ ⁽¹⁾	Typ ⁽¹⁾	Typ ⁽¹⁾	
XC7K70T	$I_{CCINTQ} + 450$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 40$	mA
XC7K160T	$I_{CCINTQ} + 550$	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 40$	mA
XC7K325T	$I_{CCINTQ} + 600$	$I_{CCAUXQ} + 80$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 40$	mA
XC7K355T	$I_{CCINTQ} + 1450$	$I_{CCAUXQ} + 109$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 81$	mA
XC7K410T	$I_{CCINTQ} + 1500$	$I_{CCAUXQ} + 125$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 90$	mA
XC7K420T	$I_{CCINTQ} + 2200$	$I_{CCAUXQ} + 180$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 108$	mA
XC7K480T	$I_{CCINTQ} + 2200$	$I_{CCAUXQ} + 180$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 108$	mA

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.

Table 8: Power Supply Ramp Time

Symbol	Description	Conditions	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 90% of V_{CCINT}		0.2	50	ms
T_{VCCO}	Ramp time from GND to 90% of V_{CCO}		0.2	50	ms
T_{VCCAUX}	Ramp time from GND to 90% of V_{CCAUX}		0.2	50	ms
T_{VCCAUX_IO}	Ramp time from GND to 90% of V_{CCAUX_IO}		0.2	50	ms
T_{CCBRAM}	Ramp time from GND to 90% of V_{CCBRAM}		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625\text{V}$	$T_J = 100^\circ\text{C}^{(1)}$	–	500	ms
		$T_J = 85^\circ\text{C}^{(1)}$	–	800	
$T_{MGTAVCC}$	Ramp time from GND to 90% of $V_{MGTAVCC}$		0.2	50	ms
$T_{MGTAVTT}$	Ramp time from GND to 90% of $V_{MGTAVTT}$		0.2	50	ms
$T_{MGTVCCAUX}$	Ramp time from GND to 90% of $V_{MGTVCCAUX}$		0.2	50	ms

Notes:

1. Based on 240,000 power cycles with nominal V_{CCO} of 3.3V or 36,500 power cycles with a worst case V_{CCO} of 3.465V.

IOB Pad Input/Output/3-State

Table 19 (3.3V high-range IOB (HR)) and **Table 20** (1.8V high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- T_{IOP} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than T_{IOTP} when the DCITERMDISABLE pin is used. In HR I/O banks, the IN_TERM termination turn-on time is always faster than T_{IOTP} when the INTERMDISABLE pin is used.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	T_{IOP}				T_{IOOP}				T_{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
LVTTL_S4	1.31	1.42	1.64	1.51	5.27	5.63	6.05	4.13	6.03	6.49	7.04	4.64	ns	
LVTTL_S8	1.31	1.42	1.64	1.51	4.45	4.83	5.30	3.86	5.21	5.69	6.29	4.38	ns	
LVTTL_S12	1.31	1.42	1.64	1.51	4.45	4.83	5.29	3.84	5.21	5.69	6.28	4.36	ns	
LVTTL_S16	1.31	1.42	1.64	1.51	3.47	3.88	4.40	3.39	4.23	4.74	5.39	3.91	ns	
LVTTL_S24	1.31	1.42	1.64	1.51	3.58	3.99	4.51	3.61	4.34	4.85	5.50	4.13	ns	
LVTTL_F4	1.31	1.42	1.64	1.51	4.70	4.98	5.29	3.58	5.46	5.84	6.28	4.09	ns	
LVTTL_F8	1.31	1.42	1.64	1.51	3.66	4.06	4.56	3.06	4.42	4.92	5.55	3.58	ns	
LVTTL_F12	1.31	1.42	1.64	1.51	3.66	4.06	4.56	3.05	4.42	4.92	5.55	3.56	ns	
LVTTL_F16	1.31	1.42	1.64	1.51	2.57	2.85	3.15	2.88	3.33	3.71	4.14	3.39	ns	
LVTTL_F24	1.31	1.42	1.64	1.51	2.41	2.64	2.89	2.94	3.17	3.50	3.88	3.45	ns	
LVDS_25 ⁽¹⁾	0.64	0.68	0.80	0.83	1.36	1.47	1.55	1.58	2.12	2.33	2.54	2.09	ns	
MINI_LVDS_25	0.68	0.70	0.79	0.83	1.36	1.47	1.55	1.59	2.12	2.33	2.54	2.11	ns	
BLVDS_25 ⁽¹⁾	0.65	0.69	0.80	0.83	1.83	2.02	2.20	2.16	2.59	2.88	3.19	2.67	ns	
RSDS_25 (point to point) ⁽¹⁾	0.63	0.68	0.79	0.83	1.36	1.48	1.55	1.59	2.12	2.34	2.54	2.11	ns	
PPDS_25 ⁽¹⁾	0.65	0.69	0.80	0.83	1.36	1.49	1.58	1.59	2.12	2.35	2.57	2.11	ns	
TMDS_33 ⁽¹⁾	0.72	0.76	0.86	0.83	1.43	1.54	1.60	1.70	2.19	2.40	2.59	2.22	ns	
PCI33_3 ⁽¹⁾	1.28	1.41	1.65	1.50	2.71	3.08	3.52	3.42	3.47	3.94	4.51	3.94	ns	
HSUL_12	0.63	0.64	0.71	0.79	2.06	2.31	2.59	2.13	2.82	3.17	3.58	2.64	ns	
DIFF_HSUL_12	0.58	0.61	0.70	0.81	1.83	2.04	2.26	1.92	2.59	2.90	3.25	2.44	ns	
HSTL_I_S	0.61	0.64	0.73	0.79	1.55	1.69	1.80	1.91	2.31	2.55	2.79	2.42	ns	
HSTL_II_S	0.61	0.64	0.73	0.78	1.21	1.34	1.43	1.70	1.97	2.20	2.42	2.22	ns	
HSTL_I_18_S	0.64	0.67	0.76	0.79	1.28	1.39	1.45	1.58	2.04	2.25	2.44	2.09	ns	
HSTL_II_18_S	0.64	0.67	0.76	0.79	1.18	1.31	1.40	1.69	1.94	2.17	2.39	2.20	ns	
DIFF_HSTL_I_S	0.63	0.67	0.77	0.78	1.42	1.54	1.61	1.84	2.18	2.40	2.60	2.36	ns	
DIFF_HSTL_II_S	0.63	0.67	0.77	0.79	1.15	1.24	1.27	1.78	1.91	2.10	2.26	2.30	ns	
DIFF_HSTL_I_18_S	0.65	0.69	0.78	0.79	1.27	1.38	1.43	1.67	2.03	2.24	2.42	2.19	ns	
DIFF_HSTL_II_18_S	0.65	0.69	0.78	0.81	1.14	1.23	1.26	1.72	1.90	2.09	2.25	2.23	ns	

Table 19: 3.3V IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
HSTL_I_F	0.61	0.64	0.73	0.79	1.10	1.19	1.23	1.41	1.86	2.05	2.22	1.92	ns	
HSTL_II_F	0.61	0.64	0.73	0.78	1.05	1.18	1.28	1.42	1.81	2.04	2.27	1.94	ns	
HSTL_I_18_F	0.64	0.67	0.76	0.79	1.05	1.18	1.28	1.44	1.81	2.04	2.27	1.95	ns	
HSTL_II_18_F	0.64	0.67	0.76	0.79	1.03	1.14	1.23	1.42	1.79	2.00	2.22	1.94	ns	
DIFF_HSTL_I_F	0.63	0.67	0.77	0.78	1.09	1.18	1.22	1.48	1.85	2.04	2.21	2.00	ns	
DIFF_HSTL_II_F	0.63	0.67	0.77	0.79	1.02	1.11	1.14	1.48	1.78	1.97	2.13	2.00	ns	
DIFF_HSTL_I_18_F	0.65	0.69	0.78	0.79	1.08	1.17	1.21	1.48	1.84	2.03	2.20	2.00	ns	
DIFF_HSTL_II_18_F	0.65	0.69	0.78	0.81	1.01	1.10	1.13	1.48	1.77	1.96	2.12	2.00	ns	
LVCMOS33_S4	1.31	1.40	1.60	1.54	5.23	5.61	6.09	4.13	5.99	6.47	7.08	4.64	ns	
LVCMOS33_S8	1.31	1.40	1.60	1.54	4.46	4.85	5.33	3.84	5.22	5.71	6.32	4.36	ns	
LVCMOS33_S12	1.31	1.40	1.60	1.54	3.46	3.89	4.42	3.41	4.22	4.75	5.41	3.92	ns	
LVCMOS33_S16	1.31	1.40	1.60	1.54	3.06	3.43	3.88	3.72	3.82	4.29	4.87	4.23	ns	
LVCMOS33_F4	1.31	1.40	1.60	1.54	4.70	5.01	5.36	3.58	5.46	5.87	6.35	4.09	ns	
LVCMOS33_F8	1.31	1.40	1.60	1.54	3.62	4.04	4.56	3.06	4.38	4.90	5.55	3.58	ns	
LVCMOS33_F12	1.31	1.40	1.60	1.54	2.57	2.85	3.15	2.88	3.33	3.71	4.14	3.39	ns	
LVCMOS33_F16	1.31	1.40	1.60	1.54	2.44	2.69	2.96	2.88	3.20	3.55	3.95	3.39	ns	
LVCMOS25_S4	1.08	1.16	1.32	1.36	4.49	4.80	5.16	3.44	5.25	5.66	6.15	3.95	ns	
LVCMOS25_S8	1.08	1.16	1.32	1.36	3.66	4.04	4.49	3.20	4.42	4.90	5.48	3.72	ns	
LVCMOS25_S12	1.08	1.16	1.32	1.36	2.77	3.10	3.49	2.80	3.53	3.96	4.48	3.31	ns	
LVCMOS25_S16	1.08	1.16	1.32	1.36	3.24	3.62	4.09	3.14	4.00	4.48	5.08	3.66	ns	
LVCMOS25_F4	1.08	1.16	1.32	1.36	3.96	4.31	4.72	3.06	4.72	5.17	5.71	3.58	ns	
LVCMOS25_F8	1.08	1.16	1.32	1.36	2.43	2.87	3.42	2.50	3.19	3.73	4.41	3.02	ns	
LVCMOS25_F12	1.08	1.16	1.32	1.36	2.23	2.63	3.13	2.48	2.99	3.49	4.12	3.00	ns	
LVCMOS25_F16	1.08	1.16	1.32	1.36	1.92	2.17	2.45	2.33	2.68	3.03	3.44	2.84	ns	
LVCMOS18_S4	0.64	0.66	0.74	0.87	3.24	3.45	3.66	1.91	4.00	4.31	4.65	2.42	ns	
LVCMOS18_S8	0.64	0.66	0.74	0.87	2.58	2.91	3.31	2.50	3.34	3.77	4.30	3.02	ns	
LVCMOS18_S12	0.64	0.66	0.74	0.87	2.58	2.91	3.31	2.50	3.34	3.77	4.30	3.02	ns	
LVCMOS18_S16	0.64	0.66	0.74	0.87	1.82	2.03	2.24	1.84	2.58	2.89	3.23	2.36	ns	
LVCMOS18_S24 ⁽¹⁾	0.64	0.66	0.74	0.87	1.74	1.92	2.08	1.92	2.50	2.78	3.07	2.44	ns	
LVCMOS18_F4	0.64	0.66	0.74	0.87	3.12	3.31	3.49	1.77	3.88	4.17	4.48	2.28	ns	
LVCMOS18_F8	0.64	0.66	0.74	0.87	1.91	2.13	2.36	2.00	2.67	2.99	3.35	2.52	ns	
LVCMOS18_F12	0.64	0.66	0.74	0.87	1.91	2.13	2.36	2.00	2.67	2.99	3.35	2.52	ns	
LVCMOS18_F16	0.64	0.66	0.74	0.87	1.52	1.68	1.81	1.72	2.28	2.54	2.80	2.23	ns	
LVCMOS18_F24 ⁽¹⁾	0.64	0.66	0.74	0.87	1.34	1.46	1.55	1.66	2.10	2.32	2.54	2.17	ns	
LVCMOS15_S4	0.66	0.69	0.81	0.90	3.48	3.74	4.03	2.22	4.24	4.60	5.02	2.73	ns	
LVCMOS15_S8	0.66	0.69	0.81	0.90	2.37	2.67	3.01	2.41	3.13	3.53	4.00	2.92	ns	
LVCMOS15_S12	0.66	0.69	0.81	0.90	1.83	2.03	2.23	1.91	2.59	2.89	3.22	2.42	ns	

Table 20: 1.8V IOB High Performance (HP) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
LVCMOS12_F8	0.64	0.67	0.78	0.95	1.27	1.42	1.55	1.41	1.91	2.18	2.37	2.02	ns	
LVDCI_18	0.47	0.50	0.60	0.86	1.99	2.15	2.35	2.44	2.62	2.91	3.17	3.05	ns	
LVDCI_15	0.59	0.62	0.73	0.87	1.98	2.23	2.58	2.40	2.62	2.99	3.40	3.01	ns	
LVDCI_DV2_18	0.47	0.50	0.60	0.87	1.99	2.15	2.34	1.86	2.62	2.90	3.17	2.48	ns	
LVDCI_DV2_15	0.59	0.62	0.73	0.87	1.98	2.23	2.58	1.83	2.62	2.99	3.40	2.44	ns	
HSLVDCI_18	0.68	0.72	0.82	0.86	1.99	2.15	2.35	2.43	2.62	2.91	3.17	3.04	ns	
HSLVDCI_15	0.68	0.72	0.82	0.84	1.98	2.23	2.58	2.27	2.62	2.99	3.40	2.88	ns	
SSTL18_I_S	0.68	0.72	0.82	0.86	1.02	1.15	1.24	1.41	1.66	1.90	2.07	2.02	ns	
SSTL18_II_S	0.68	0.72	0.82	0.87	1.17	1.29	1.37	1.55	1.81	2.05	2.19	2.16	ns	
SSTL18_I_DCI_S	0.68	0.72	0.82	0.76	0.92	1.06	1.17	1.32	1.56	1.82	1.99	1.93	ns	
SSTL18_II_DCI_S	0.68	0.72	0.82	0.78	0.88	0.98	1.08	1.26	1.51	1.74	1.90	1.87	ns	
SSTL18_II_T_DCI_S	0.68	0.72	0.82	0.78	0.92	1.06	1.17	1.32	1.56	1.82	1.99	1.93	ns	
SSTL15_S	0.68	0.72	0.82	0.81	0.94	1.06	1.15	1.32	1.58	1.82	1.97	1.93	ns	
SSTL15_DCI_S	0.68	0.72	0.82	0.78	0.94	1.06	1.15	1.30	1.57	1.82	1.97	1.91	ns	
SSTL15_T_DCI_S	0.68	0.72	0.82	0.80	0.94	1.06	1.15	1.30	1.57	1.82	1.97	1.91	ns	
SSTL135_S	0.69	0.72	0.82	0.89	0.97	1.10	1.19	1.35	1.60	1.85	2.01	1.96	ns	
SSTL135_DCI_S	0.69	0.72	0.82	0.84	0.97	1.09	1.19	1.33	1.60	1.85	2.01	1.94	ns	
SSTL135_T_DCI_S	0.69	0.72	0.82	0.84	0.97	1.09	1.19	1.33	1.60	1.85	2.01	1.94	ns	
SSTL12_S	0.69	0.72	0.82	0.95	0.96	1.09	1.18	1.33	1.60	1.84	2.00	1.94	ns	
SSTL12_DCI_S	0.69	0.72	0.82	0.91	1.03	1.17	1.27	1.33	1.66	1.92	2.09	1.94	ns	
SSTL12_T_DCI_S	0.69	0.72	0.82	0.91	1.03	1.17	1.27	1.33	1.66	1.92	2.09	1.94	ns	
DIFF_SSTL18_I_S	0.75	0.79	0.92	0.89	1.02	1.15	1.24	1.43	1.66	1.90	2.07	2.04	ns	
DIFF_SSTL18_II_S	0.75	0.79	0.92	0.89	1.17	1.29	1.37	1.55	1.81	2.05	2.19	2.16	ns	
DIFF_SSTL18_I_DCI_S	0.75	0.79	0.92	0.76	0.92	1.06	1.17	1.40	1.56	1.82	1.99	2.01	ns	
DIFF_SSTL18_II_DCI_S	0.75	0.79	0.92	0.75	0.88	0.98	1.08	1.33	1.51	1.74	1.90	1.94	ns	
DIFF_SSTL18_II_T_DCI_S	0.75	0.79	0.92	0.76	0.92	1.06	1.17	1.40	1.56	1.82	1.99	2.01	ns	
DIFF_SSTL15_S	0.68	0.72	0.82	0.89	0.94	1.06	1.15	1.32	1.58	1.82	1.97	1.93	ns	
DIFF_SSTL15_DCI_S	0.68	0.72	0.82	0.75	0.94	1.06	1.15	1.30	1.57	1.82	1.97	1.91	ns	
DIFF_SSTL15_T_DCI_S	0.68	0.72	0.82	0.76	0.94	1.06	1.15	1.38	1.57	1.82	1.97	1.99	ns	
DIFF_SSTL135_S	0.69	0.72	0.82	0.91	0.97	1.10	1.19	1.35	1.60	1.85	2.01	1.96	ns	
DIFF_SSTL135_DCI_S	0.69	0.72	0.82	0.76	0.97	1.09	1.19	1.33	1.60	1.85	2.01	1.94	ns	
DIFF_SSTL135_T_DCI_S	0.69	0.72	0.82	0.76	0.97	1.09	1.19	1.43	1.60	1.85	2.01	2.04	ns	
DIFF_SSTL12_S	0.69	0.72	0.82	0.91	0.96	1.09	1.18	1.33	1.60	1.84	2.00	1.94	ns	
DIFF_SSTL12_DCI_S	0.69	0.72	0.82	0.78	1.03	1.17	1.27	1.33	1.66	1.92	2.09	1.94	ns	
DIFF_SSTL12_T_DCI_S	0.69	0.72	0.82	0.80	1.03	1.17	1.27	1.41	1.66	1.92	2.09	2.02	ns	

Table 27: IO_FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
IO_FIFO Clock to Out Delays						
T _{OFFCKO_DO}	RDCLK to Q outputs	0.51	0.56	0.63	0.81	ns
T _{CKO_FLAGS}	Clock to IO_FIFO Flags	0.59	0.62	0.81	0.77	ns
Setup/Hold						
T _{CCK_D/T_{CKC_D}}	D inputs to WRCLK	0.43/-0.01	0.47/-0.01	0.53/-0.01	0.76/-0.05	ns
T _{IFFCCK_WREN/T_{IFFCKC_WREN}}	WREN to WRCLK	0.39/-0.01	0.43/-0.01	0.50/-0.01	0.70/-0.05	ns
T _{OFFCCK_RDEN/T_{OFFCKC_RDEN}}	RDEN to RDCLK	0.49/0.01	0.53/0.02	0.61/0.02	0.79/-0.02	ns
Minimum Pulse Width						
T _{PWH_IO_FIFO}	RESET, RDCLK, WRCLK	0.81	0.92	1.08	1.29	ns
T _{PWL_IO_FIFO}	RESET, RDCLK, WRCLK	0.81	0.92	1.08	1.29	ns
Maximum Frequency						
F _{MAX}	RDCLK and WRCLK	533.05	470.37	400.00	333.33	MHz

DSP48E1 Switching Characteristics

Table 32: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock						
T _{DSPDCK_A_AREG} /T _{DSPCKD_A_AREG}	A input to A register CLK	0.24/ 0.12	0.27/ 0.14	0.31/ 0.16	0.38/ 0.12	ns
T _{DSPDCK_B_BREG} /T _{DSPCKD_B_BREG}	B input to B register CLK	0.28/ 0.13	0.32/ 0.14	0.39/ 0.15	0.51/ 0.16	ns
T _{DSPDCK_C_CREG} /T _{DSPCKD_C_CREG}	C input to C register CLK	0.15/ 0.15	0.17/ 0.17	0.20/ 0.20	0.31/ 0.21	ns
T _{DSPDCK_D_DREG} /T _{DSPCKD_D_DREG}	D input to D register CLK	0.21/ 0.19	0.27/ 0.22	0.35/ 0.26	0.46/ 0.20	ns
T _{DSPDCK_ACIN_AREG} /T _{DSPCKD_ACIN_AREG}	ACIN input to A register CLK	0.21/ 0.12	0.24/ 0.14	0.27/ 0.16	0.31/ 0.12	ns
T _{DSPDCK_BCIN_BREG} /T _{DSPCKD_BCIN_BREG}	BCIN input to B register CLK	0.22/ 0.13	0.25/ 0.14	0.30/ 0.15	0.34/ 0.16	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock						
T _{DSPDCK_{A,B}_MREG_MULT} / T _{DSPCKD_B_MREG_MULT}	{A, B} input to M register CLK using multiplier	2.04/ -0.01	2.34/ -0.01	2.79/ -0.01	3.66/ -0.06	ns
T _{DSPDCK_{A,B}_ADREG} /T _{DSPCKD_D_ADREG}	{A, D} input to AD register CLK	1.09/ -0.02	1.25/ -0.02	1.49/ -0.02	1.94/ -0.23	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock						
T _{DSPDCK_{A,B}_PREG_MULT} / T _{DSPCKD_{A,B}_PREG_MULT}	{A, B} input to P register CLK using multiplier	3.41/ -0.24	3.90/ -0.24	4.64/ -0.24	5.89/ -0.41	ns
T _{DSPDCK_D_PREG_MULT} / T _{DSPCKD_D_PREG_MULT}	D input to P register CLK using multiplier	3.33/ -0.62	3.81/ -0.62	4.53/ -0.62	5.70/ -1.42	ns
T _{DSPDCK_{A,B}_PREG} / T _{DSPCKD_{A,B}_PREG}	A or B input to P register CLK not using multiplier	1.47/ -0.24	1.68/ -0.24	2.00/ -0.24	2.37/ -0.41	ns
T _{DSPDCK_C_PREG} /T _{DSPCKD_C_PREG}	C input to P register CLK not using multiplier	1.30/ -0.22	1.49/ -0.22	1.78/ -0.22	2.11/ -0.36	ns
T _{DSPDCK_PCIN_PREG} /T _{DSPCKD_PCIN_PREG}	PCIN input to P register CLK	1.12/ -0.13	1.28/ -0.13	1.52/ -0.13	1.81/ -0.21	ns
Setup and Hold Times of the CE Pins						
T _{DSPDCK_{CEA;CEB}_{AREG;BREG}} / T _{DSPCKD_{CEA;CEB}_{AREG;BREG}}	{CEA; CEB} input to {A; B} register CLK	0.30/ 0.05	0.36/ 0.06	0.44/ 0.09	0.55/ 0.09	ns
T _{DSPDCK_CEC_CREG} /T _{DSPCKD_CEC_CREG}	CEC input to C register CLK	0.24/ 0.08	0.29/ 0.09	0.36/ 0.11	0.43/ 0.11	ns
T _{DSPDCK_CED_DREG} /T _{DSPCKD_CED_DREG}	CED input to D register CLK	0.31/ -0.02	0.36/ -0.02	0.44/ -0.02	0.58/ 0.12	ns
T _{DSPDCK_CEM_MREG} /T _{DSPCKD_CEM_MREG}	CEM input to M register CLK	0.26/ 0.15	0.29/ 0.17	0.33/ 0.20	0.39/ 0.25	ns
T _{DSPDCK_CEP_PREG} /T _{DSPCKD_CEP_PREG}	CEP input to P register CLK	0.31/ 0.01	0.36/ 0.01	0.45/ 0.01	0.54/ 0.00	ns

Table 32: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of the RST Pins						
$T_{DSPDCK_RSTA; RSTB_AREG; BREG}/T_{DSPCKD_RSTA; RSTB_AREG; BREG}$	{RSTA, RSTB} input to {A, B} register CLK	0.34/ 0.10	0.39/ 0.11	0.47/ 0.13	0.53/ 0.34	ns
$T_{DSPDCK_RSTC_CREG}/T_{DSPCKD_RSTC_CREG}$	RSTC input to C register CLK	0.06/ 0.22	0.07/ 0.24	0.08/ 0.26	0.08/ 0.31	ns
$T_{DSPDCK_RSTD_DREG}/T_{DSPCKD_RSTD_DREG}$	RSTD input to D register CLK	0.37/ 0.06	0.42/ 0.06	0.50/ 0.07	0.57/ 0.07	ns
$T_{DSPDCK_RSTM_MREG}/T_{DSPCKD_RSTM_MREG}$	RSTM input to M register CLK	0.18/ 0.18	0.20/ 0.21	0.23/ 0.24	0.24/ 0.29	ns
$T_{DSPDCK_RSTP_PREG}/T_{DSPCKD_RSTP_PREG}$	RSTP input to P register CLK	0.24/ 0.01	0.26/ 0.01	0.30/ 0.01	0.37/ 0.00	ns
Combinatorial Delays from Input Pins to Output Pins						
$T_{DSPDO_A_CARRYOUT_MULT}$	A input to CARRYOUT output using multiplier	3.21	3.69	4.39	5.60	ns
$T_{DSPDO_D_P_MULT}$	D input to P output using multiplier	3.15	3.61	4.30	5.44	ns
$T_{DSPDO_A_P}$	A input to P output not using multiplier	1.30	1.48	1.76	2.10	ns
$T_{DSPDO_C_P}$	C input to P output	1.13	1.30	1.55	1.84	ns
Combinatorial Delays from Input Pins to Cascading Output Pins						
$T_{DSPDO_A; B_{ACOUT; BCOUT}}$	{A, B} input to {ACOUT, BCOUT} output	0.47	0.53	0.63	0.75	ns
$T_{DSPDO_A, B_CARRYCASOUT_MULT}$	{A, B} input to CARRYCASOUT output using multiplier	3.44	3.94	4.69	5.96	ns
$T_{DSPDO_D_CARRYCASOUT_MULT}$	D input to CARRYCASOUT output using multiplier	3.36	3.85	4.58	5.77	ns
$T_{DSPDO_A, B_CARRYCASOUT}$	{A, B} input to CARRYCASOUT output not using multiplier	1.50	1.72	2.04	2.44	ns
$T_{DSPDO_C_CARRYCASOUT}$	C input to CARRYCASOUT output	1.34	1.53	1.83	2.18	ns
Combinatorial Delays from Cascading Input Pins to All Output Pins						
$T_{DSPDO_ACIN_P_MULT}$	ACIN input to P output using multiplier	3.09	3.55	4.24	5.42	ns
$T_{DSPDO_ACIN_P}$	ACIN input to P output not using multiplier	1.16	1.33	1.59	2.07	ns
$T_{DSPDO_ACIN_ACOUT}$	ACIN input to ACOUT output	0.32	0.37	0.45	0.53	ns
$T_{DSPDO_ACIN_CARRYCASOUT_MULT}$	ACIN input to CARRYCASOUT output using multiplier	3.30	3.79	4.52	5.76	ns
$T_{DSPDO_ACIN_CARRYCASOUT}$	ACIN input to CARRYCASOUT output not using multiplier	1.37	1.57	1.87	2.40	ns
$T_{DSPDO_PCIN_P}$	PCIN input to P output	0.94	1.08	1.29	1.54	ns
$T_{DSPDO_PCIN_CARRYCASOUT}$	PCIN input to CARRYCASOUT output	1.15	1.32	1.57	1.88	ns
Clock to Outs from Output Register Clock to Output Pins						
$T_{DSPCKO_P_PREG}$	CLK PREG to P output	0.33	0.35	0.39	0.45	ns
$T_{DSPCKO_CARRYCASOUT_PREG}$	CLK PREG to CARRYCASOUT output	0.44	0.50	0.59	0.71	ns

Table 32: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Clock to Outs from Pipeline Register Clock to Output Pins						
T _{DSPCKO_P_MREG}	CLK MREG to P output	1.42	1.64	1.96	2.31	ns
T _{DSPCKO_CARRYCASCOU_MREG}	CLK MREG to CARRYCASCOU output	1.63	1.87	2.24	2.65	ns
T _{DSPCKO_P_ADREG_MULT}	CLK ADREG to P output using multiplier	2.30	2.63	3.13	3.90	ns
T _{DSPCKO_CARRYCASCOU_ADREG_MULT}	CLK ADREG to CARRYCASCOU output using multiplier	2.51	2.87	3.41	4.23	ns
Clock to Outs from Input Register Clock to Output Pins						
T _{DSPCKO_P_AREG_MULT}	CLK AREG to P output using multiplier	3.34	3.83	4.55	5.80	ns
T _{DSPCKO_P_BREG}	CLK BREG to P output not using multiplier	1.39	1.59	1.88	2.24	ns
T _{DSPCKO_P_CREG}	CLK CREG to P output not using multiplier	1.43	1.64	1.95	2.32	ns
T _{DSPCKO_P_DREG_MULT}	CLK DREG to P output using multiplier	3.32	3.80	4.51	5.74	ns
Clock to Outs from Input Register Clock to Cascading Output Pins						
T _{DSPCKO_{ACOUT; BCOUT}_{AREG; BREG}}	CLK (ACOUT, BCOUT) to {A,B} register output	0.55	0.62	0.74	0.87	ns
T _{DSPCKO_CARRYCASCOU_{AREG, BREG}_MULT}	CLK (AREG, BREG) to CARRYCASCOU output using multiplier	3.55	4.06	4.84	6.13	ns
T _{DSPCKO_CARRYCASCOU_BREG}	CLK BREG to CARRYCASCOU output not using multiplier	1.60	1.82	2.16	2.58	ns
T _{DSPCKO_CARRYCASCOU_DREG_MULT}	CLK DREG to CARRYCASCOU output using multiplier	3.52	4.03	4.79	6.07	ns
T _{DSPCKO_CARRYCASCOU_CREG}	CLK CREG to CARRYCASCOU output	1.64	1.88	2.23	2.65	ns
Maximum Frequency						
F _{MAX}	With all registers used	741.84	650.20	547.95	429.37	MHz
F _{MAX_PATDET}	With pattern detector	627.35	549.75	463.61	365.90	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG	412.20	360.75	303.77	248.32	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect	374.25	327.65	276.01	225.73	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG	468.82	408.66	342.70	263.44	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect	468.82	408.66	342.70	263.44	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG)	306.84	267.81	225.02	177.15	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect	285.23	249.13	209.38	165.32	MHz

Table 42: Clock-Capable Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with MMCM</i> .							
TICKOFMMCMCC	Clock-capable clock input and OUTFF <i>with MMCM</i>	XC7K70T	0.95	0.95	0.95	1.74	ns
		XC7K160T	0.96	0.96	0.96	1.78	ns
		XC7K325T	1.00	1.00	1.00	1.82	ns
		XC7K355T	1.00	1.00	1.00	1.78	ns
		XC7K410T	1.00	1.00	1.00	1.82	ns
		XC7K420T	1.07	1.07	1.07	1.82	ns
		XC7K480T	1.07	1.07	1.07	1.82	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 43: Clock-Capable Clock Input to Output Delay With PLL

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with PLL</i> .							
TICKOFPLLCC	Clock-capable clock input and OUTFF <i>with PLL</i>	XC7K70T	0.84	0.84	0.84	1.45	ns
		XC7K160T	0.89	0.89	0.89	1.54	ns
		XC7K325T	0.89	0.89	0.89	1.54	ns
		XC7K355T	0.89	0.89	0.89	1.50	ns
		XC7K410T	0.89	0.89	0.89	1.54	ns
		XC7K420T	0.96	0.96	0.96	1.54	ns
		XC7K480T	0.96	0.96	0.96	1.54	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. PLL output jitter is already included in the timing calculation.

Table 44: Pin-to-Pin, Clock-to-Out using BUFI0

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with BUFI0</i> .						
TICKOFC0	Clock-to-Out of I/O clock for HR I/O banks	4.93	5.52	6.20	6.97	ns
	Clock-to-Out of I/O clock for HP I/O banks	4.85	5.44	6.11	6.90	ns

Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

Table 45: Global Clock Input Setup and Hold Without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾								
T_{PSFD}/T_{PHFD}	Full Delay (Legacy Delay or Default Delay) Global Clock Input and IFF ⁽²⁾ without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks	XC7K70T	2.83/-0.29	2.95/-0.29	3.15/-0.29	4.96/-0.33	ns	
		XC7K160T	3.17/-0.35	3.29/-0.35	3.55/-0.35	5.54/-0.49	ns	
		XC7K325T	2.83/-0.06	2.94/-0.06	3.15/-0.06	5.18/-0.14	ns	
		XC7K355T	3.26/-0.32	3.41/-0.32	3.67/-0.32	5.84/-0.49	ns	
		XC7K410T	3.43/-0.34	3.59/-0.34	3.88/-0.34	6.21/-0.54	ns	
		XC7K420T	3.37/-0.27	3.48/-0.27	3.76/-0.27	6.00/-0.52	ns	
		XC7K480T	3.37/-0.27	3.48/-0.27	3.76/-0.27	6.00/-0.52	ns	

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

Table 46: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾								
$T_{PSMMCMCC}/T_{PHMMCMCC}$	No Delay clock-capable clock input and IFF ⁽²⁾ with MMCM	XC7K70T	2.39/-0.22	2.65/-0.22	2.94/-0.22	2.21/-0.44	ns	
		XC7K160T	2.49/-0.20	2.77/-0.20	3.07/-0.20	2.38/-0.47	ns	
		XC7K325T	2.55/-0.16	2.85/-0.16	3.14/-0.16	2.60/-0.47	ns	
		XC7K355T	2.43/-0.16	2.73/-0.16	3.00/-0.16	2.47/-0.43	ns	
		XC7K410T	2.55/-0.16	2.84/-0.16	3.14/-0.16	2.58/-0.47	ns	
		XC7K420T	2.47/-0.09	2.73/-0.09	3.02/-0.09	2.40/-0.41	ns	
		XC7K480T	2.47/-0.09	2.73/-0.09	3.02/-0.09	2.40/-0.41	ns	

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 52 summarizes the DC specifications of the clock input of the GTX transceiver. Consult [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) for further details.

Table 52: GTX Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V _{IDIFF}	Differential peak-to-peak input voltage	250	—	2000	mV
R _{IN}	Differential input resistance	—	100	—	Ω
C _{EXT}	Required external AC coupling capacitor	—	100	—	nF

GTX Transceiver Switching Characteristics

Consult [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) for further information.

Table 53: GTX Transceiver Performance

Symbol	Description	Output Divider	Speed Grade								Units	
			1.0V				0.9V					
			-3		-2/-2L		-1 ⁽¹⁾		-2L ⁽²⁾			
			Package Type									
			FF	FB	FF	FB	FF	FB	FF	FB		
F _{GTXMAX} ⁽³⁾	Maximum GTX transceiver data rate		12.5	6.6	10.3125	6.6	8.0	6.6	6.6	6.6	Gb/s	
F _{GTXMIN} ⁽³⁾	Minimum GTX transceiver data rate		0.500	0.500	0.500	0.500	0.500	0.500	0.500	0.500	Gb/s	
F _{GTXCRANGE}	CPLL line rate range	1	3.2–6.6								Gb/s	
		2	1.6–3.3								Gb/s	
		4	0.8–1.65								Gb/s	
		8	0.5–0.825								Gb/s	
		16	N/A								Gb/s	
F _{GTXQRANGE1}	QPLL line rate range 1	1	5.93–8.0	5.93–6.6	5.93–8.0	5.93–6.6	5.93–8.0	5.93–6.6	5.93–6.6		Gb/s	
		2	2.965–4.0		2.965–4.0		2.965–4.0		2.965–3.3		Gb/s	
		4	1.4825–2.0		1.4825–2.0		1.4825–2.0		1.4825–1.65		Gb/s	
		8	0.74125–1.0		0.74125–1.0		0.74125–1.0		0.74125–0.825		Gb/s	
		16	N/A		N/A		N/A		N/A		Gb/s	
F _{GTXQRANGE2}	QPLL line rate range 2 ⁽⁴⁾	1	9.8–12.5	N/A	9.8–10.3125	N/A	N/A		N/A		Gb/s	
		2	4.9–6.25		4.9–5.15625		N/A		N/A		Gb/s	
		4	2.45–3.125		2.45–2.578125		N/A		N/A		Gb/s	
		8	1.225–1.5625		1.225–1.2890625		N/A		N/A		Gb/s	
		16	0.6125–0.78125		0.6125–0.64453125		N/A		N/A		Gb/s	
F _{GCPLLRANGE}	GTX transceiver CPLL frequency range		1.6–3.3		1.6–3.3		1.6–3.3		1.6–3.3		GHz	
F _{GQPLLRANGE1}	GTX transceiver QPLL frequency range 1		5.93–8.0		5.93–8.0		5.93–8.0		5.93–6.6		GHz	

Table 53: GTX Transceiver Performance (Cont'd)

Symbol	Description	Output Divider	Speed Grade								Units	
			1.0V				0.9V					
			-3	-2/-2L	-1 ⁽¹⁾	-2L ⁽²⁾						
			Package Type									
			FF	FB	FF	FB	FF	FB	FF	FB		
F _{GQPLL RANGE2}	GTX transceiver QPLL frequency range 2		9.8–12.5	9.8–10.3125	N/A	N/A					GHz	

Notes:

1. The -1 speed grade requires a 4-byte internal data width for operation above 5.0 Gb/s.
2. The -2L (0.9V) speed grade requires a 4-byte internal data width for operation above 3.8 Gb/s.
3. Data rates between 8.0 Gb/s and 9.8 Gb/s are not available.
4. For QPLL line rate range 2, the maximum line rate with the divider N set to 66 is 10.3125Gb/s.

Table 54: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
F _{GTXDRPCLK}	GTXDRPCLK maximum frequency	175.01	175.01	156.25	125.00	MHz	

Table 55: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F _{GCLK}	Reference clock frequency range	-3 speed grade	60	—	700	MHz
		All other speed grades	60	—	670	MHz
T _{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T _{FCLK}	Reference clock fall time	80% – 20%	—	200	—	ps
T _{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	50	60	%

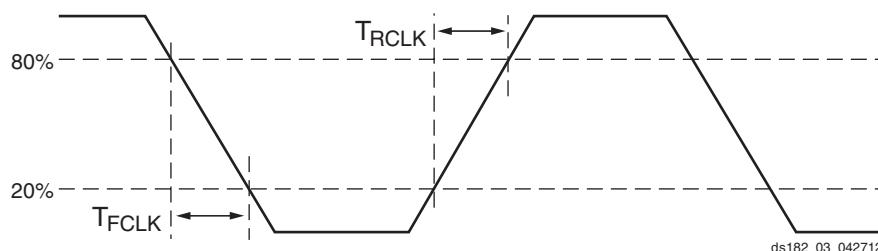


Figure 3: Reference Clock Timing Parameters

Table 59: GTX Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F_{GTXRX}	Serial data rate	RX oversampler not enabled	0.500	—	F_{GTXMAX}	Gb/s
$T_{RXELECIDLE}$	Time for RXELECIDLE to respond to loss or restoration of data		—	10	—	ns
RX_{OOBVDP}	OOB detect threshold peak-to-peak		60	—	150	mV
RX_{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	-5000	—	0	ppm
RX_{RL}	Run length (CID)		—	—	512	UI
RX_{PPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	-1250	—	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	-700	—	700	ppm
		Bit rates > 8.0 Gb/s	-200	—	200	ppm
SJ Jitter Tolerance⁽²⁾						
$JT_{SJ12.5}$	Sinusoidal Jitter (QPLL) ⁽³⁾	12.5 Gb/s	0.3	—	—	UI
$JT_{SJ11.18}$	Sinusoidal Jitter (QPLL) ⁽³⁾	11.18 Gb/s	0.3	—	—	UI
$JT_{SJ10.32}$	Sinusoidal Jitter (QPLL) ⁽³⁾	10.32 Gb/s	0.3	—	—	UI
$JT_{SJ9.95}$	Sinusoidal Jitter (QPLL) ⁽³⁾	9.95 Gb/s	0.3	—	—	UI
$JT_{SJ9.8}$	Sinusoidal Jitter (QPLL) ⁽³⁾	9.8 Gb/s	0.3	—	—	UI
$JT_{SJ8.0}$	Sinusoidal Jitter (QPLL) ⁽³⁾	8.0 Gb/s	0.44	—	—	UI
$JT_{SJ6.6_QPLL}$	Sinusoidal Jitter (QPLL) ⁽³⁾	6.6 Gb/s	0.48	—	—	UI
$JT_{SJ6.6_CPLL}$	Sinusoidal Jitter (CPLL) ⁽³⁾	6.6 Gb/s	0.44	—	—	UI
$JT_{SJ5.0}$	Sinusoidal Jitter (CPLL) ⁽³⁾	5.0 Gb/s	0.44	—	—	UI
$JT_{SJ4.25}$	Sinusoidal Jitter (CPLL) ⁽³⁾	4.25 Gb/s	0.44	—	—	UI
$JT_{SJ3.75}$	Sinusoidal Jitter (CPLL) ⁽³⁾	3.75 Gb/s	0.44	—	—	UI
$JT_{SJ3.2}$	Sinusoidal Jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	—	—	UI
$JT_{SJ3.2L}$	Sinusoidal Jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁵⁾	0.45	—	—	UI
$JT_{SJ2.5}$	Sinusoidal Jitter (CPLL) ⁽³⁾	2.5 Gb/s ⁽⁶⁾	0.5	—	—	UI
$JT_{SJ1.25}$	Sinusoidal Jitter (CPLL) ⁽³⁾	1.25 Gb/s ⁽⁷⁾	0.5	—	—	UI
JT_{SJ500}	Sinusoidal Jitter (CPLL) ⁽³⁾	500 Mb/s	0.4	—	—	UI
SJ Jitter Tolerance with Stressed Eye⁽²⁾						
$JT_{TJSE3.2}$	Total Jitter with Stressed Eye ⁽⁸⁾	3.2 Gb/s	0.70	—	—	UI
$JT_{TJSE6.6}$		6.6 Gb/s	0.70	—	—	UI
$JT_{SJSE3.2}$	Sinusoidal Jitter with Stressed Eye ⁽⁸⁾	3.2 Gb/s	0.1	—	—	UI
$JT_{SJSE6.6}$		6.6 Gb/s	0.1	—	—	UI

Notes:

1. Using RXOUT_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 10 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
5. CPLL frequency at 1.6 GHz and RXOUT_DIV = 1.
6. CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
7. CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
8. Composite jitter with RX and LPM or DFE mode.

GTX Transceiver Protocol Jitter Characteristics

For Table 60 through Table 65, the [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) contains recommended settings for optimal usage of protocol specific characteristics.

Table 60: Gigabit Ethernet Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
Gigabit Ethernet Transmitter Jitter Generation				
Total transmitter jitter (T_TJ)	1250	–	0.24	UI
Gigabit Ethernet Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	1250	0.749	–	UI

Table 61: XAUI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
XAUI Transmitter Jitter Generation				
Total transmitter jitter (T_TJ)	3125	–	0.35	UI
XAUI Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	3125	0.65	–	UI

Table 62: PCI Express Protocol Characteristics⁽¹⁾

Standard	Description	Line Rate (Mb/s)	Min	Max	Units	
PCI Express Transmitter Jitter Generation						
PCI Express Gen 1	Total transmitter jitter	2500	–	0.25	UI	
PCI Express Gen 2	Total transmitter jitter	5000	–	0.25	UI	
PCI Express Gen 3 ⁽²⁾	Total transmitter jitter uncorrelated	8000	–	31.25	ps	
	Deterministic transmitter jitter uncorrelated		–	12	ps	
PCI Express Receiver High Frequency Jitter Tolerance						
PCI Express Gen 1	Total receiver jitter tolerance	2500	0.65	–	UI	
PCI Express Gen 2 ⁽³⁾	Receiver inherent timing error	5000	0.40	–	UI	
	Receiver inherent deterministic timing error		0.30	–	UI	
PCI Express Gen 3 ⁽²⁾	Receiver sinusoidal jitter tolerance	0.03 MHz–1.0 MHz	8000	1.00	–	UI
		1.0 MHz–10 MHz		Note 4	–	UI
		10 MHz–100 MHz		0.10	–	UI

Notes:

1. Tested per card electromechanical (CEM) methodology.
2. PCI-SIG 3.0 certification and compliance test boards are currently not available.
3. Using common REFCLK.
4. Between 1 MHz and 10 MHz the minimum sinusoidal jitter roll-off with a slope of 20dB/decade.

Table 65: CPRI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
CPRI Transmitter Jitter Generation				
Total transmitter jitter	614.4	–	0.35	UI
	1228.8	–	0.35	UI
	2457.6	–	0.35	UI
	3072.0	–	0.35	UI
	4915.2	–	0.3	UI
	6144.0	–	0.3	UI
	9830.4	–	Note 1	UI
CPRI Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	614.4	0.65	–	UI
	1228.8	0.65	–	UI
	2457.6	0.65	–	UI
	3072.0	0.65	–	UI
	4915.2	0.95	–	UI
	6144.0	0.95	–	UI
	9830.4	Note 1	–	UI

Notes:

- Tested per SFP+ specification, see [Table 64](#).

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 66: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
FPIPECLK	Pipe clock maximum frequency	250.00	250.00	250.00	250.00	MHz
FUSERCLK	User clock maximum frequency	500.00	500.00	250.00	250.00	MHz
FUSERCLK2	User clock 2 maximum frequency	250.00	250.00	250.00	250.00	MHz
FRPCLK	DRP clock maximum frequency	250.00	250.00	250.00	250.00	MHz

Revision History

The following table shows the revision history for this document:

Date	Version	Description
03/01/11	1.0	Initial Xilinx release.
04/01/11	1.1	Added the XC7K355T, XC7K420T, and XC7K480T devices throughout data sheet. Added the extended temperature range discussion to page 1 . Updated V_{CCAUX_IO} in Table 2 . Edits to clarify Power-On/Off Power Supply Sequencing power sequencing discussion. Added I_{CCAUX_IO} and I_{CCBRAM} to Table 6 and Table 7 . Updated MMCM_ F_{INDUTY} and added $F_{INJITTER}$, $T_{OUTJITTER}$, $T_{EXTFDVAR}$, and Note 3 to Table 38 . Removed the SBG324 package from Table 50 . Updated the Notice of Disclaimer .
10/04/11	1.2	Replaced -1L with -2L throughout this data sheet. Updated Min/Max values and removed Note 5 from Table 2 . Clarified Power-On/Off Power Supply Sequencing power sequencing discussion including adding $T_{VCO2VCCAUX}$ to Table 8 . Updated V_{ICM} in Table 12 and Table 13 . Added Note 1 to table 12. Updated Table 69 including adding Note 1 . Added <i>Absolute Maximum Ratings for GTX Transceivers</i> . Revised the reference clock maximum frequency (F_{GCLK}) in Table 55 . Added Table 57 . Added LVTTL and removed SSTL135_II and SSTL15_II specifications from Table 19 . Removed HSTL_III from Table 20 . Removed the <i>I/O Standard Adjustment Measurement Methodology</i> section. Use IBIS for more accurate information and measurements. Updated $T_{IDELAYPAT_JIT}$ in Table 26 . Added T_{AS}/T_{AH} to Table 28 . Added $T_{RDCK_DI_WF_NC}/T_{RCKD_DI_WF_NC}$ and $T_{RDCK_DI_RF}/T_{RCKD_DI_RF}$ to Table 31 . Completely updated Table 68 . Updated the AC Switching Characteristics in Table 19 , Table 20 , Table 21 , Table 22 , Table 23 , Table 24 , Table 26 through Table 38 , Table 40 though Table 37 , and Table 67 .
11/03/11	1.3	Revised the V_{OCM} specification in Table 12 . Updated the AC Switching Characteristics based upon the ISE 13.3 v1.02 speed specification throughout document including Table 19 and Table 20 . Added MMCM_ $T_{FBDELAY}$ while adding MMCM_ to the symbol names of a few specifications in Table 38 and PLL to the symbol names in Table 39 . In Table 40 through Table 47 , updated the pin-to-pin descriptions with the SSTL15 standard. Updated units in Table 49 .
02/13/12	1.4	Updated summary description on page 1 . In Table 2 , revised V_{CCO} for the 3.3V HR I/O banks and updated T_j . Added typical values to Table 3 . Updated the notes in Table 6 . Added MGTAVCC, MGTAVTT, and MGTVCCAUX power supply ramp times to Table 8 . Rearranged Table 9 , added Mobile_DDR, HSTL_I_18, HSTL_II_18, HSUL_12, SSTL135_R, SSTL15_R, and SSTL12 and removed DIFF_SSTL135, DIFF_SSTL18_I, DIFF_SSTL18_II, DIFF_HSTL_I, and DIFF_HSTL_II. Added Table 10 and Table 11 . Revised the specifications in Table 12 and Table 13 . Updated the eFUSE Programming Conditions section and removed the endurance table. Added the IO_FIFO Switching Characteristics table. Revised I_{CCADC} and updated Note 1 in Table 67 . Revised DDR LVDS transmitter data width in Table 16 . Updated the AC Switching Characteristics based upon the ISE 13.4 v1.03 speed specification throughout document. Removed notes from Table 28 as they are no longer applicable. Updated specifications in Table 68 . Updated Note 1 in Table 37 . In the GTX Transceiver DC Input and Output Levels section: Revised V_{IN} , and added I_{DCIN} and I_{DCOUT} to Table 51 . Added Note 4 to Table 53 . In Table 55 , revised F_{GCLK} , removed T_{PHASE} , and added T_{DLOCK} . Revised specifications and added Note 2 to Table 57 . Added Table 58 and Table 59 along with GTX Transceiver Protocol Jitter Characteristics in Table 60 through Table 65 .
05/23/12	1.5	Reorganized entire data sheet including adding Table 44 and Table 48 . Updated T_{SOL} in Table 1 . Updated I_{BATT} and added R_{IN_TERM} to Table 3 . Added values to Table 6 and Table 7 . Updated Power-On/Off Power Supply Sequencing , page 6 with regards to GTX transceivers. Updated many parameters in Table 9 including SSTL135 and SSTL135_R. Removed V_{OX} column and added DIFF_HSUL_12 to Table 11 . Updated V_{OL} in Table 12 . Updated Table 16 and removed notes 2 and 3. Updated Table 17 . Updated the AC Switching Characteristics based upon the ISE 14.1 v1.04 for the -3, -2, -2L (1.0V), -1, and -2L (0.9V) speed specifications throughout the document. In Table 31 , updated Reset Delays section including Note 10 and Note 11 . Added data for T_{LOCK} and T_{DLOCK} in Table 55 . Updated many of the XADC specifications in Table 67 and added Note 2 . Updated and moved <i>Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK</i> section from Table 68 to Table 38 and Table 39 .